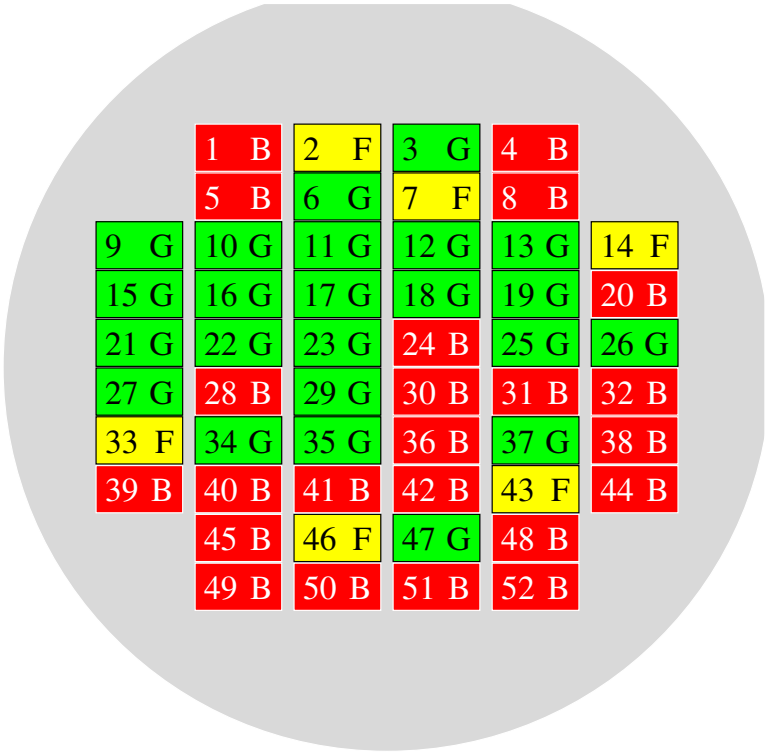
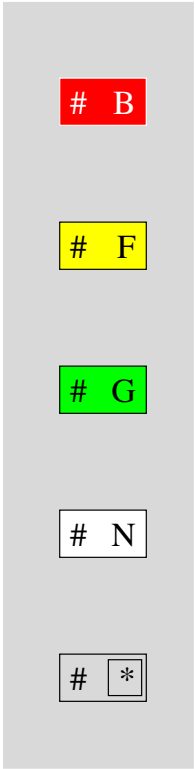
Die quality map for wafer 111 s/n: 21316-07-19

Date: 03/01/99